L Number	Hits	Search Text	DB	Time stamp
-	1	"878554"	US-PGPUB	2003/12/25 08:43
	11	714/741.ccls.	US-PGPUB	2003/12/24
-	125	714/741.ccls.	USPAT; US-PGPUB	2003/12/24
-	13	714/741.ccls. and good with simulation	USPAT; US-PGPUB	2003/12/24
-	38	714/741.ccls. and (good reference) with simulation	USPAT; US-PGPUB	2003/12/25 07:47
-	40	714/741.ccls. and (good reference gold golden) with (simulation simulate simulates simulated simulating)	USPAT; US-PGPUB	2003/12/25 07:49
-	12	714/741.ccls. and (good reference gold golden) with (simulation simulate simulates simulated simulating) and ((fault defect) adj simulation)	USPAT; US-PGPUB	2003/12/25 07:52
-	12	714/741.ccls. and (good reference gold golden) with (simulation simulate simulates simulated simulating simulator) and ((fault defect) adj (simulation simulator))	USPAT; US-PGPUB	2003/12/25 07:56
	12	714/741.ccls. and ((logic circuit) adj (simulation simulator)) and ((fault defect) adj (simulation simulator))	USPAT; US-PGPUB	2003/12/25 07:57
-	12	714/741.ccls. and ((logic circuit logical) adj (simulation simulator)) and ((fault defect) adj (simulation simulator))	USPAT; US-PGPUB	2003/12/25 08:31
-	623	714/741.ccls. ((fault defect) adj (simulation simulator))	USPAT; US-PGPUB	2003/12/25 08:20
-	33	714/741.ccls. and ((fault defect) adj (simulation simulator))	USPAT; US-PGPUB	2003/12/25 08:21
-	5	(714/741.ccls. and ((logic circuit logical) adj (simulation simulator)) and ((fault defect) adj (simulation simulator))) not (714/741.ccls. and (good reference gold golden) with (simulation simulate simulates simulated simulating simulator) and ((fault defect) adj (simulation simulator)))	USPAT; US-PGPUB	2003/12/25 08:21
-	14	714/741.ccls. and ((logic circuit logical (fault adj free)) adj (simulation simulator)) and ((fault defect) adj (simulation simulator))	USPAT; US-PGPUB	2003/12/25 08:35
-	13	714/741.ccls. and ((logic circuit logical (fault adj free)) adj (simulation simulator)) and ((fault defect) adj (simulation simulator)) and (fault faults)	USPAT; US-PGPUB	2003/12/25 08:35
-	13	714/741.ccls. and ((logic circuit logical (fault adj free)) adj (simulation simulator)) and ((fault defect) adj (simulation simulator)) and (fault faults)	USPAT; US-PGPUB	2003/12/25 08:35
-	14	714/741.ccls. and ((logic circuit logical (fault adj free)) adj (simulation simulator)) and ((fault defect) adj (simulation simulator)) and (fault faults defect defects)	USPAT; US-PGPUB	2003/12/25 08:47
-	1	"878554" and value with node	US-PGPUB	2003/12/25 08:44
-	7	714/741.ccls. and ((I gic circuit logical (fault adj free)) adj (simulation simulator)) and ((fault defect) adj (simulation simulat r)) and (fault faults defect defects) and (node n des)	USPAT; US-PGPUB	2003/12/25 08:51

-	94	(((logic circuit   gical (fault adj free)) adj (simulati n simulat r)) and ((fault defect) adj	USPAT; US-PGPUB	2003/12/25 08:52
		(simulation simulator)) and (fault faults defect		
		defects) and (node n des)) not (714/741.ccls.		
		and ((I gic circuit logical (fault adj free)) adj		
		(simulati n simulator)) and ((fault defect) adj		
		(simulation simulat r)) and (fault faults defect		
		defects) and (node nodes))		
-	101	((logic circuit logical (fault adj free)) adj	USPAT;	2003/12/25
ı		(simulation simulator)) and ((fault defect) adj	US-PGPUB	09:06
		(simulation simulator)) and (fault faults defect		
		defects) and (node nodes)		
-	106	((logic circuit logical (fault adj free)) adj	USPAT;	2003/12/25
		(simulation simulator)) and ((fault defect) adj	US-PGPUB;	09:17
		(simulation simulator)) and (fault faults defect	EPO; JPO;	
		defects) and (node nodes)	DERWENT;	
			IBM_TDB	
-	96	((logic circuit logical (fault adj free)) adj	USPAT;	2003/12/25
		(simulation simulator)) and ((fault defect) adj	US-PGPUB;	11:43
		(simulation simulator)) and (fault faults defect	EPO; JPO;	
		defects) and (node nodes) and ((test adj vector)	DERWENT;	
	1.0	pattern)	IBM_TDB	2005//2/05
•	10	(((logic circuit logical (fault adj free)) adj	USPAT;	2003/12/25
		(simulation simulator)) and ((fault defect) adj	US-PGPUB;	09:19
		(simulation simulator)) and (fault faults defect	EPO; JPO;	
		defects) and (node nodes)) not (((logic circuit	DERWENT;	
		logical (fault adj free)) adj (simulation simulator)) and ((fault defect) adj (simulation simulator)) and	IBM_TDB	
		(fault faults defect defects) and (node nodes) and		
		((test adj vector) pattern))		
-	12	((logic circuit logical (fault adj free)) adj	USPAT;	2003/12/25
	'-	(simulation simulator)) and ((fault defect) adj	US-PGPUB;	09:57
		(simulation simulator)) and (fault faults defect	EPO; JPO;	07.57
		defects) and (node nodes) and ((test adj vector)	DERWENT;	
		pattern) and (backtracing backtrace backtraced	IBM TDB	
		backtraces (back near (trace traces traced		
		tracing)))		
-	15	((logic circuit logical (fault adj free)) adj	USPAT;	2003/12/25
		(simulation simulator)) and ((fault defect) adj	US-PGPUB;	10:01
		(simulation simulator)) and (fault faults defect	EPO; JPO;	
		defects) and (node nodes) and ((test adj vector)	DERWENT;	
		pattern) and (backtracing backtrace backtraced	IBM_TDB	
		backtraces backwardtrace backwardtraces	_	
		backwardtraced backwardtracing ((back backward)		
		near (trace traces traced tracing)))		
-	15	((logic circuit logical (fault adj free)) adj	USPAT;	2003/12/25
		(simulation simulator)) and ((fault defect) adj	us-PGPUB;	10:43
		(simulation simulator)) and (fault faults defect	EPO; JPO;	
		defects) and (node nodes) and ((test adj vector)	DERWENT;	
		pattern) and (backtracing backtrace backtraced	IBM_TDB	
		backtraces backwardtrace backwardtraces		
		backwardtraced backwardtracing ((back backward)		
		near (trace traces traced tracing drive)))		<u> </u>

-	22	((I gic circuit logical (fault adj free)) adj (simulati n simulat r)) and ((fault defect) adj	USPAT; US-PGPUB;	2003/12/25 11:48
		(simulati n simulator)) and (fault faults defect	EPO; JPO;	
		defects) and (node nodes) and ((test adj vector)	DERWENT;	
		pattern) and (backtracing backtrace backtraced	IBM_TDB	
		backtraces backwardtrace backwardtraces backwardtraced backwardtracing backtrack		
		backtracks backtracking backtracked ((back		
		backward) near (trace traces traced tracing drive		
		track tracks tracking tracked)))		
-	30	(simulation simulator) with ((fault faults) near	USPAT;	2003/12/25
		(injection inject injecting injects injected))	US-PGPUB;	11:55
			EPO; JPO;	
			DERWENT;	
	2	(simulation simulator) with ((fault faults defect	IBM_TDB USPAT;	2003/12/25
-		defects) near (injection inject injecting injects	US-PGPUB;	10:44
		injected)) and (node nodes) and ((test adj vector)	EPO; JPO;	10.11
		pattern) and (backtracing backtrace backtraced	DERWENT;	
		backtraces backwardtrace backwardtraces	IBM_TDB	
		backwardtraced backwardtracing ((back backward)		
		near (trace traces traced tracing drive)))		
-	44	((logic circuit logical (fault adj free) (good adj	USPAT;	2003/12/25
		machine)) adj (simulation simulator)) and ((fault defect) adj (simulation simulator)) and (fault faults	US-PGPUB; EPO; JPO;	11:44
		defect defects) and (node nodes) and ((test adj	DERWENT;	
		vector) pattern) and scan	IBM TDB	
-	46	(((logic circuit logical (fault adj free)) adj	USPĀT;	2003/12/25
		(simulation simulator)) (good adj machine)) and	US-PGPUB;	11:55
		((fault defect) adj (simulation simulator)) and	EPO; JPO;	
		(fault faults defect defects) and (node nodes) and	DERWENT;	
	1.7	((test adj vector) pattern) and scan	IBM_TDB	2007/42/25
- 	16	(((logic circuit logical (fault adj free)) adj (simulation simulator)) (good adj machine)) and	USPAT; US-PGPUB;	2003/12/25 11:46
		((fault defect) adj (simulation simulator)) and	EPO; JPO;	11.70
}		(fault faults defect defects) and (node nodes) and	DERWENT;	
		((test adj vector) pattern) and ((partial full) adj	IBM_TDB	
		scan)		
-	4	((logic circuit logical (fault adj free)) adj	USPAT;	2003/12/26
		(simulation simulator)) and ((fault defect) adj	US-PGPUB;	07:12
		(simulation simulator)) and (fault faults defect defects) and (node nodes) and ((test adj vector)	EPO; JPO; DERWENT;	
		pattern) and (backtracing backtrace backtraced	IBM TDB	
		backtraces backwardtrace backwardtraces	.555	
		backwardtraced backwardtracing backtrack		
		backtracks backtracking backtracked ((back		
		backward) near (trace traces traced tracing drive		
		track tracks tracking tracked))) and ((partial full)		
	7	adj scan) (((logic circuit logical (fault adj free)) adj	USPAT;	2003/12/26
	'	(((logic circuit logical (fault adj free)) adj (simulation simulator)) (good adj machine)) and	US-PGPUB;	07:11
		((fault defect) adj (simulation simulator)) and	EPO; JPO;	
		(backtracing backtrace backtraced backtraces	DERWENT;	
		backwardtrace backwardtraces backwardtraced	IBM_TDB	
		backwardtracing backtrack backtracks backtracking		
		backtracked ((back backward) near (trace traces		
		traced tracing drive track tracks tracking tracked))) and ((partial full) adj scan)		
L		trackeu/// and ((partial full) auf SCAN)	L	L

-	1	(true adj value adj (simulati n simulator)) and ((fault defect) adj (simulation simulator)) and (backtracing backtrace backtraced backtraces backwardtrace backwardtraced backwardtracing backtrack backtracks backtracking backtracked ((back backward) near (trace traces traced tracing drive track tracks tracking	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/12/26 07:12
-	3	tracked))) and ((partial full) adj scan) (simulation simulator) with ((fault faults) near (injection inject injecting injects injected)) and (backtracing backtrace backtraced backtraces backwardtrace backwardtraces backwardtraced backwardtracing backtrack backtracks backtracking backtracked ((back backward) near (trace traces traced tracing drive track tracks tracking	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/12/26 07:12
		tracked))) and ((partial full) adj scan)		